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LTC2312-14

### 14-Bit, 500ksps Serial Sampling ADC in TSOT

- 500ksps Throughput Rate
- **No Cycle Latency**
- <sup>n</sup> **Guaranteed 14-Bit No Missing Codes**
- **n** Single 3V or 5V Supply
- <sup>n</sup> **Low Noise: 77.5dB SNR**
- Low Power: 9mW at 500ksps and 3V Supply
- Low Drift (20ppm/°C Maximum) 2.048V or 4.096V **Internal Reference**
- Sleep Mode with  $<$  1µA Typical Supply Current
- $\blacksquare$  Nap Mode with Quick Wake-Up < 1 Conversion
- Separate 1.8V to 5V Digital I/O Supply
- High Speed SPI-Compatible Serial I/O
- Guaranteed Operation from  $-40^{\circ}$ C to 125 $^{\circ}$ C
- 8-Lead TSOT-23 Package

### **APPLICATIONS**

- **n** Communication Systems
- $\blacksquare$  High Speed Data Acquisition
- $\blacksquare$  Handheld Terminal Interface
- $\blacksquare$  Medical Imaging
- Uninterrupted Power Supplies
- Battery Operated Systems
- $\blacksquare$  Automotive

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### FEATURES DESCRIPTION

The LTC®2312-14 is a 14-bit, 500ksps, serial sampling A/D converter that draws only 3.2mA from a single 3V or 5V supply. The LTC2312-14 contains an integrated low drift reference and reference buffer providing a low cost, high performance (20ppm/°C maximum) and space saving solution. The LTC2312-14 achieves outstanding AC performance of 77dB SINAD and –85dB THD while sampling at 500ksps. The extremely high sample rate-topower ratio makes the LTC2312-14 ideal for compact, low power, high speed systems. The supply current decreases at lower sampling rates as the device automatically enters nap mode after conversions.

The LTC2312-14 has a high speed SPI-compatible serial interface that supports 1.8V, 2.5V, 3V and 5V logic. The fast 500ksps throughput with no-cycle latency makes the LTC2312-14 ideally suited for a wide variety of high speed applications.

#### **Complete 14-/12-Bit Pin-Compatible SAR ADC Family**



### TYPICAL APPLICATION

**5V Supply, Internal Reference, 500ksps, 14-Bit Sampling ADC**



#### **16k Point FFT, fS = 500ksps, fIN = 259kHz**



### ABSOLUTE MAXIMUM RATINGS PIN CONFIGURATION

**(Notes 1, 2)**





### ORDER INFORMATION

#### **Lead Free Finish**



TRM = 500 pieces. \*Temperature grades are identified by a label on the shipping container.

Consult LTC Marketing for parts specified with wider operating temperature ranges.

Consult LTC Marketing for information on lead based finish parts.

For more information on lead free part marking, go to: http://www.linear.com/leadfree/

For more information on tape and reel specifications, go to: http://www.linear.com/tapeandreel/



### **ELECTRICAL CHARACTERISTICS** The  $\bullet$  denotes the specifications which apply over the full operating

**temperature range, otherwise specifications are at TA = 25°C. (Note 4)**



#### CONVERTER CHARACTERISTICS The  $\bullet$  denotes the specifications which apply over the full operating **temperature range, otherwise specifications are at TA = 25°C. (Note 4)**



#### **DYNAMIC ACCURACY** The  $\bullet$  denotes the specifications which apply over the full operating temperature range, **otherwise specifications are at TA = 25°C and AIN = –1dBFS. (Note 4)**





### REFERENCE INPUT/OUTPUT The  $\bullet$  denotes the specifications which apply over the full operating temperature

**range, otherwise specifications are at TA = 25°C. (Note 4)**



### **DIGITAL INPUTS AND DIGITAL OUTPUTS** The  $\bullet$  denotes the specifications which apply over the

**full operating temperature range, otherwise specifications are at TA = 25°C. (Note 4)**



#### POWER REQUIREMENTS The  $\bullet$  denotes the specifications which apply over the full operating temperature **range, otherwise specifications are at TA = 25°C. (Note 4)**





### ADC TIMING CHARACTERISTICS The  $\bullet$  denotes the specifications which apply over the full operating

**temperature range, otherwise specifications are at TA = 25°C. (Note 4)**



**Note 1.** Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

**Note 2**. All voltage values are with respect to ground.

**Note 3.** When these pin voltages are taken below ground or above V<sub>DD</sub>  $(A_{IN}, REF)$  or  $OV<sub>DD</sub>$  (SCK, CONV, SDO) they will be clamped by internal diodes. This product can handle input currents up to 100mA below ground or above  $V_{DD}$  or  $OV_{DD}$  without latch-up.

**Note 4.**  $V_{DD} = 5V$ ,  $OV_{DD} = 2.5V$ ,  $f_{SMPL} = 500kHz$ ,  $f_{SCK} = 20MHz$ ,  $A_{IN} =$ –1dBFS and internal reference unless otherwise noted.

**Note 5.** Integral nonlinearity is defined as the deviation of a code from a straight line passing through the actual endpoints of the transfer curve. The deviation is measured from the center of the quantization band.

**Note 6.** Typical RMS noise at code transitions.

**Note 7.** Parameter tested and guaranteed at  $OV<sub>DD</sub> = 2.5V$ . All input signals are specified with t<sub>r</sub> = t<sub>f</sub> = 1ns (10% to 90% of OV<sub>DD</sub>) and timed from a voltage level of OV<sub>DD</sub>/2.

**Note 8.** All timing specifications given are with a 10pF capacitance load. Load capacitances greater than this will require a digital buffer.

**Note 9.** The time required for the output to cross the  $V_{OH}$  or  $V_{OL}$  voltage.

**Note 10.** Guaranteed by design, not subject to test.

**Note 11.** Recommended operating conditions.



### TYPICAL PERFORMANCE CHARACTERISTICS **TA = 25°C, VDD = 5V, OVDD = 2.5V, fSMPL = 500ksps,**

**unless otherwise noted.**









**DC Histogram Near Mid-Scale (Code 8192)**



#### **SNR, SINAD vs Input Frequency (100kHz to 1.2MHz)**



**SNR, SINAD vs Temperature,** 

SNR

SINAD

**fIN = 259kHz**

–55 –35

71

74 73 72

78 77

79

SNR, SINAD (dBFS) 75 76

SNR, SINAD (dBFS)

#### **THD, Harmonics vs Input Frequency (100kHz to 1.2MHz)**



**THD, Harmonics vs Temperature, fIN = 259kHz**



231214fa



TEMPERATURE (°C)

SNR

SINAD

–15 5 25 45 65 85 105 125

 $V<sub>DD</sub> = 5V$ 

231214 G08

 $V<sub>DD</sub> = 3V$ 

#### TYPICAL PERFORMANCE CHARACTERISTICS **TA = 25°C, VDD = 5V, OVDD = 2.5V, fSMPL = 500ksps, unless otherwise noted.**









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### **TYPICAL PERFORMANCE CHARACTERISTICS**  $T_A = 25^{\circ}$ C, V<sub>DD</sub> = 5V, OV<sub>DD</sub> = 2.5V, f<sub>SMPL</sub> = 500ksps,

**unless otherwise noted.**



### PIN FUNCTIONS

 $V_{DD}$  (Pin 1): Power Supply. The ranges of  $V_{DD}$  are 2.7V to 3.6V and 4.75V to 5.25V. Bypass  $V_{DD}$  to GND with a 2.2µF ceramic chip capacitor.

**REF (Pin 2):** Reference Input/Output. The REF pin voltage defines the input span of the ADC, OV to  $V_{REF}$ . By default, REF is an output pin and produces a reference voltage  $V_{RFF}$  of either 2.048V or 4.096V depending on  $V_{DD}$  (see Table 2). Bypass to GND with a 2.2 $\mu$ F, low ESR, high quality ceramic chip capacitor. The REF pin may be overdriven with a voltage at least 50mV higher than the internal reference voltage output.

**GND (Pin 3):** Ground. The GND pin must be tied directly to a solid ground plane.

**A<sub>IN</sub>** (Pin 4): Analog Input. A<sub>IN</sub> is a single-ended input with respect to GND with a range from 0V to  $V_{\text{RFF}}$ .

**OV<sub>DD</sub>** (Pin 5): I/O Interface Digital Power. The OV<sub>DD</sub> range is 1.71V to 5.25V. This supply is nominally set to the same supply as the host interface (1.8V, 2.5V, 3.3V or 5V). Bypass to GND with a 2.2µF ceramic chip capacitor. **SDO (Pin 6):** Serial Data Output. The A/D conversion result is shifted out on SDO as a serial data stream with the MSB first through the LSB last. The data stream consists of 14 bits of conversion data followed by trailing zeros. There is no cycle latency. Logic levels are determined by  $O(V_{DD})$ .

**SCK (Pin 7):** Serial Data Clock Input. The SCK serial clock synchronizes the serial data transfer. SDO data transitions on the falling edge of SCK. Logic levels are determined by  $OV<sub>DD</sub>$ .

**CONV (Pin 8):** Convert Input. This active high signal starts a conversion on the rising edge. The conversion is timed via an internal oscillator. The device automatically powers down following the conversion process. The SDO pin is in high impedance when CONV is a logic high. Bringing CONV low enables the SDO pin and outputs the MSB. Subsequent bits of the conversion data are read out serially on the falling edge of SCK. A logic low on CONV also places the sample-and-holdintosamplemode. Logic levels are determined by  $O(V_{DD})$ .



### BLOCK DIAGRAM



### TIMING DIAGRAMS







231214 TD03 231214 TD04 **Figure 3. SDO Data Valid Hold After SCK**↓



231214 TD01 231214 TD02 **Figure 2. SDO Into Hi-Z After CONV**↑



**Figure 4. SDO Data Valid Access After SCK**↓



#### **Overview**

The LTC2312-14 is a low noise, high speed, 14-bit successive approximation register (SAR) ADC. The LTC2312-14 operates from a single 3V or 5V supply and provides a low drift (20ppm/°C maximum), internal reference and reference buffer. The internal reference buffer is automatically configured with a 2.048V span in low supply range (2.7V to 3.6V) and with a 4.096V span in the high supply range (4.75V to 5.25V). The LTC2312-14 samples at a 500ksps rate and supports a 20MHz serial data read clock. The LTC2312-14 achieves excellent dynamic performance (77dB SINAD, 85dB THD) while dissipating only 15mW from a 5V supply up to the 500ksps conversion rate. The LTC2312-14 outputs the conversion data with no cycle latency onto the SDO pin. The SDO pin output logic levels are supplied by the dedicated  $\text{OV}_{DD}$  supply pin which has a wide supply range (1.71V to 5.25V) allowing the LTC2312-14 to communicate with 1.8V, 2.5V, 3V or 5V systems. The LTC2312-14 automatically switches to nap mode following the conversion process to save power. The device also provides a sleep power-down mode through serial interface control to reduce power dissipation during long inactive periods.

### **Serial Interface**

The LTC2312-14 communicates with microcontrollers, DSPs and other external circuitry via a 3-wire interface. A rising CONV edge starts the conversion process which is timed via an internal oscillator. Following the conversion process the device automatically switches to nap mode to save power as shown in Figure 7. This feature saves considerable power for the LTC2312-14 operating at lower sampling rates. As shown in Figures 5 and 6, it is recommended to hold SCK static low or high during  $t_{\text{CONV}}$ . Note that CONV must be held high for the entire minimum conversion time  $(t_{\text{CONV}})$ . A falling CONV edge enables SDO and outputs the MSB. Subsequent SCK falling edges clock out the remaining data as shown in Figures 5 and 6. Data is serially output MSB first through LSB last, followed by trailing zeros if further SCK falling edges are applied.

### **Serial Data Output (SDO)**

The SDO output is always forced into the high impedance state while CONV is high. The falling edge of CONV enables SDO and also places the sample and hold into sample mode. The A/D conversion result is shifted out on the SDO pin as a serial data stream with the MSB first. The MSB is output on SDO on the falling edge of CONV. Delay  $t_3$  is the data valid access time for the MSB. The following 13 bits of conversion data are shifted out on SDO on the falling edge of SCK. Delay  $t_4$  is the data valid access time for output data shifted out on the falling edge of SCK. There is no data latency. Subsequent falling SCK edges applied after the LSB is output will output zeros indefinitely on the SDO pin.

The output swing on the SDO pin is controlled by the  $O(V_{DD}$  pin voltage and supports a wide operating range from 1.71V to 5.25V independent of the  $V_{DD}$  pin voltage.

#### **Power Considerations**

The LTC2312-14 provides two sets of power supply pins: the analog power supply  $(V_{DD})$  and the digital input/output interface power supply ( $\text{OV}_{\text{DD}}$ ). The flexible  $\text{OV}_{\text{DD}}$  supply allows the LTC2312-14 to communicate with any digital logic operating between 1.8V and 5V, including 2.5V and 3.3V systems.

### **Entering Nap/Sleep Mode**

Pulsing CONV two times and holding SCK static places the LTC2312-14 into nap mode. Pulsing CONV four times and holding SCK static places the LTC2312-14 into sleep mode. In sleep mode, all bias circuitry is shut down, including the internal bandgap and reference buffer, and only leakage currents remain (0.2µA typical). Because the reference buffer is externally bypassed with a large capacitor (2.2µF), the LTC2312-14 requires a significant wait time (1.1ms) to recharge this capacitance before an accurate conversion can be made. In contrast, nap mode does not power down the internal bandgap or reference buffer allowing for a fast wake-up and accurate conversion within one conversion clock cycle. Supply current during nap mode is nominally 2mA.



**Figure 5. LTC2312-14 Serial Interface Timing Diagram (SCK Low During t<sub>CONV</sub>)** 



**Figure 6. LTC2312-14 Serial Interface Timing Diagram (SCK High During t<sub>CONV</sub>)** 



**Figure 7. LTC2312-14 Nap Mode Power-Down Following Conversion for**  $t_{\text{CONV}} > t_{\text{CONV-MIN}}$ 



#### **Exiting Nap/Sleep Mode**

Waking up the LTC2312-14 from either nap or sleep mode, as shown in Figures 8 and 9, requires SCK to be pulsed one time. A conversion cycle  $(t_{ACO})$  may be started immediately following nap mode as shown in Figure 8. A period of time allowing the reference voltage to recover must follow waking up from sleep mode as shown in Figure 9. The wait period required before initiating a conversion for the recommended value of  $C_{\text{RFF}}$  of 2.2µF is 1.1ms.

#### **Power Supply Sequencing**

The LTC2312-14 does not have any specific power supply sequencing requirements. Care should be taken to observe the maximum voltage relationships described in the Absolute Maximum Ratings section.

#### **Single-Ended Analog Input Drive**

The analog input of the LTC2312-14 is easy to drive. The input draws only one small current spike while charging the sample-and-hold capacitor following the falling edge of CONV. During the conversion, the analog input draws only a small leakage current. If the source impedance of the driving circuit is low, then the input of the LTC2312-14 can be driven directly. As the source impedance increases, so will the acquisition time. For minimum acquisition time

with high source impedance, a buffer amplifier should be used. The main requirement is that the amplifier driving the analog input must settle after the small current spike before the next conversion starts. Settling time must be less than  $t_{ACQ-MIN}$  (700ns) for full performance at the maximumthroughputrate. While choosinganinput amplifier, also keep in mind the amount of noise and harmonic distortion the amplifier contributes.

#### **Choosing an Input Amplifier**

Choosing an input amplifier is easy if a few requirements are taken into consideration. First, to limit the magnitude of the voltage spike seen by the amplifier from charging the sampling capacitor, choose an amplifier that has a low output impedance (<50Ω) at the closed-loop bandwidth frequency. For example, if an amplifier is used in a gain of 1 and has a unity-gain bandwidth of 50MHz, then the output impedance at 50MHz must be less than 50Ω. The second requirement is that the closed-loop bandwidth must be greater than 50MHz to ensure adequate small signal settling for full throughput rate. If slower op amps are used, more time for settling can be provided by increasing the time between conversions. The best choice for an op amp to drive the LTC2312-14 will depend on the application. Generally, applications fall into two categories: AC applications where dynamic specifications are most



**Figure 9. LTC2312-14 Entering/Exiting Sleep Mode**



critical and time domain applications where DC accuracy and settling time are most critical. The following list is a summary of the op amps that are suitable for driving the LTC2312-14. (More detailed information is available on the Linear Technology website at www.linear.com.)

**LT6230:** 215MHz GBWP, –80dBc Distortion at 1MHz, Unity-Gain Stable, Rail-to-Rail Input and Output, 3.5mA/ Amplifier, 1.1nV/√Hz.

**LT6200:** 165MHzGBWP, –85dBcDistortionat 1MHz, Unity-Gain Stable, R-R In and Out, 15mA/Amplifier, 0.95nV/√Hz.

**LT1818/1819:** 400MHzGBWP, –85dBcDistortionat 5MHz, Unity-Gain Stable, 9mA/Amplifier, Single/Dual Voltage Mode Operational Amplifier.

#### **Input Drive Circuits**

The analog input of the LTC2312-14 is designed to be driven single-ended with respect to GND. A low impedance source can directly drive the high impedance analog input of the LTC2312-14 without gain error. A high impedance source should be buffered to minimize settling time during acquisition and to optimize the distortion performance of the ADC.

For best performance, a buffer amplifier should be used to drive the analog input of the LTC2312-14. The amplifier provides low output impedance to allow for fast settling of the analog signal during the acquisition phase. It also provides isolation between the signal source and the ADC inputs which draw a small current spike during acquisition.

#### **Input Filtering**

The noise and distortion of the buffer amplifier and other circuitry must be considered since they add to the ADC noise and distortion. Noisy input circuitry should be filtered prior to the analog inputs to minimize noise. A simple 1-pole RC filter is sufficient for many applications.

Large filter RC time constants slow down the settling at the analog inputs. It is important that the overall RC time constants be short enough to allow the analog inputs to completely settle to  $>14$ -bit resolution within the minimum acquisition time  $(t_{ACO-MIN})$  of 700ns.

A simple 1-pole RC filter is sufficient for many applications. For example, Figure 10 shows a recommended singleended buffered drive circuit using the LT1818 in unity gain mode. The 470pF capacitor from  $A_{IN}$  to ground and 50 $\Omega$  source resistor limits the input bandwidth to 7MHz. The 470pF capacitor also acts as a charge reservoir for the input sample-and-hold and isolates the LT1818 from sampling glitch kick-back. The  $50\Omega$  source resistor is used to help stabilize the settling response of the drive amplifier. When choosing values of source resistance and shunt capacitance, the drive amplifier data sheet should be consulted and followed for optimum settling response. If lower input bandwidths are desired, care should be taken to optimize the settling response of the driver amplifier with higher values of shunt capacitance or series resistance. High quality capacitors and resistors should be used in the RC filter since these components can add distortion. NP0/ C0G and silver mica type dielectric capacitors have excellent linearity. Carbon surface mount resistors can generate distortion from self heating and from damage that may occur during soldering. Metal film surface mount resistors are much less susceptible to both problems. When high amplitude unwanted signals are close in frequency to the desired signal frequency, a multiple pole filter is required. High external source resistance, combined with external shunt capacitance at Pin 4 will significantly reduce the input bandwidth and may increase the required acquisition time beyond the minimum acquisition time  $(t_{ACO-MIN})$ of 700ns.



**Figure 10. RC Input Filter**

#### **ADC Reference**

A low noise, low temperature drift reference is critical to achieving the full data sheet performance of the ADC. The LTC2312-14 provides an excellent internal reference with a guaranteed 20ppm/°C maximumtemperature coefficient. For added flexibility, an external reference may also be used.

231214fa The high speed, low noise internal reference buffer is used only in the internal reference configuration. The reference



buffer must be overdriven in the external reference configuration with a voltage 50mV higher than the nominal reference output voltage in the internal configuration.

#### **Using the Internal Reference**

The internal bandgap and reference buffer are active by default when the LTC2312-14 is not in sleep mode. The reference voltage at the REF pin scales automatically with the supply voltage at the  $V_{DD}$  pin. The scaling of the reference voltage with supply is shown in Table 2.

**Table 2. Reference Voltage vs Supply Range** 

SUPPLY VOLTAGE (V <sub>DD</sub> )	<b>REF VOLTAGE (V<sub>REF</sub>)</b>
$2.7V < V_{DD} < 3.6V$	2.048V
$4.75V < V_{DD} < 5.25V$	4.096V

The reference voltage alsodetermines the full-scale analog input range of the LTC2312-14. For example, a 2.048V reference voltage will accommodate an analog input range from 0V to 2.048V. Ananaloginput voltage thatgoesbelow 0V will be coded as all zeros and an analog input voltage that exceeds 2.048V will be coded as all ones.

It is recommended that the REF pin be bypassed to ground with a low ESR, 2.2µF ceramic chip capacitor for optimum performance.

#### **External Reference**

An external reference can be used with the LTC2312-14 if better performance is required or to accommodate a larger input voltage span. The only constraints are that the external reference voltage must be 50mV higher than



the internal reference voltage (see Table 2) and must be less than or equal to the supply voltage (or 4.3V for the 5V supply range). For example, a 3.3V external reference may be used with a 3.3V  $V_{DD}$  supply voltage to provide a 3.3V analog input voltage span (i.e.  $3.3V > 2.048V + 50mV$ ). Or alternatively, a 2.5V reference may be used with a 3V supply voltage to provide a 2.5V input voltage range (i.e. 2.5V > 2.048V + 50mV). The LTC6655-3.3, LTC6655-2.5, available from Linear Technology, may be suitable for many applications requiring a high performance external reference for either 3.3V or 2.5V input spans respectively.

#### **Transfer Function**

Figure 11 depicts the transfer function of the LTC2312-14. The code transitions occur midway between successive integer LSB values (i.e. 0.5LSB, 1.5LSB, 2.5LSB… FS-0.5LSB). The output code is straight binary with  $1LSB =$ VREF/16,384.

#### **DC Performance**

The noise of an ADC can be evaluated in two ways: signal-to-noise ratio (SNR) in the frequency domain and histogram in the time domain. The LTC2312-14 excels in both. The noise in the time domain histogram is the transition noise associated with a 14-bit resolution ADC which can be measured with a fixed DC signal applied to the input of the ADC. The resulting output codes are collected over a large number of conversions. The shape of the distribution of codes will give an indication of the magnitude of the transition noise. In Figure 12, the distribution of output codes is shown for a DC input that has



**Figure 11. LTC2312-14 Transfer Function Figure 12. Histogram for 16384 Conversions**



been digitized 16,384 times. The distribution is Gaussian and the RMS code transition noise is 0.7LSB. This corresponds to a noise level of 77.5dB relative to a full scale voltage of 4.096V.

#### **Dynamic Performance**

The LTC2312-14 has excellent high speed sampling capability. Fast Fourier Transform (FFT) techniques are used to test the ADC's frequency response, distortion and noise at the rated throughput. By applying a low distortion sine wave and analyzing the digital output using an FFT algorithm, the ADC's spectral content can be examined for frequencies outside the applied fundamental. The LTC2312-14 provides guaranteed tested limits for both AC distortion and noise measurements.

#### **Signal-to-Noise and Distortion Ratio (SINAD)**

The signal-to-noise and distortion ratio (SINAD) is the ratio between the RMS amplitude of the fundamental input frequency and the RMS amplitude of all other frequency components at the A/D output. The output is band-limited to frequencies from above DC and below half the sampling frequency. Figure 14 shows the LTC2312-14 maintains a SINAD above 76dB up to an input frequency of 1.25MHz.

#### **Effective Number of Bits (ENOB)**

 $ENOB = (SINAD - 1.76)/6.02$ 

The effective number of bits (ENOB) is a measurement of the resolution of an ADC and is directly related to SINAD by the equation where ENOB is the effective number of bits of resolution and SINAD is expressed in dB:



**Figure 13. 16k Point FFT of the LTC2312-14 at fIN = 259kHz Figure 14. LTC2312-14 ENOB/SINAD vs fIN**



#### **Signal-to-Noise Ratio (SNR)**

The signal-to-noise ratio (SNR) is the ratio between the RMS amplitude of the fundamental input frequency and the RMS amplitude of all other frequency components except the first five harmonics and DC. Figure 13 shows that the LTC2312-14 achieves a typical SNR of 77.5dB at a 500kHz sampling rate with a 259kHz input frequency.

#### **Total Harmonic Distortion (THD)**

Total Harmonic Distortion (THD) is the ratio of the RMS sum of all harmonics of the input signal to the fundamental itself. The out-of-band harmonics alias into the frequency band between DC and half the sampling frequency ( $f_{SMP1}/2$ ). THD is expressed as:

$$
THD = 20\log \frac{\sqrt{V2^2 + V3^2 + V4^2 + V_N^2}}{V1}
$$

where V1 is the RMS amplitude of the fundamental frequency and V2 through  $V_N$  are the amplitudes of the second through Nth harmonics. THD versus Input Frequency is shown in the Typical Performance Characteristics section. The LTC2312-14 has excellent distortion performance well beyond the Nyquist frequency.





#### **Intermodulation Distortion (IMD)**

If the ADC input signal consists of more than one spectral component, the ADC transfer function nonlinearity can produce intermodulation distortion (IMD) in addition to THD. IMD is the change in one sinusoidal input caused by the presence of another sinusoidal input at a different frequency.

If two pure sine waves of frequencies  $\mathsf{f}_\mathsf{a}$  and  $\mathsf{f}_\mathsf{b}$  are applied to the ADC input, nonlinearities in the ADC transfer function can create distortion products at the sum and difference frequencies m  $\bullet$  f<sub>a</sub>  $\pm$  n  $\bullet$  f<sub>b</sub>, where m and n = 0, 1, 2, 3, etc. For example, the 2nd order IMD terms include  $(f_a \pm f_b)$ . If the two input sine waves are equal in magnitude, the value (in decibels) of the 2nd order IMD products can be expressed by the following formula:

 $IMD(f_a \pm f_b) = 20 \cdot log[V_A (f_a \pm f_b)/V_A (f_a)]$ 

The LTC2312-14 has excellent IMD, as shown in Figure 15.



**Figure 15. LTC2312-14 IMD Plot**

### **Spurious Free Dynamic Range (SFDR)**

The spurious free dynamic range is the largest spectral component excluding DC and the input signal. This value is expressed in decibels relative to the RMS value of a full-scale input signal.

#### **Full-Power and –3dB Input Linear Bandwidth**

The full-power bandwidth is the input frequency at which the amplitude of the reconstructed fundamental is reduced by 3dB for a full-scale input signal.

The –3dB linear bandwidth is the input frequency at which the SINAD has dropped to 74dB (12 effective bits). The LTC2312-14 has been designed to optimize the input bandwidth, allowing the ADC to under-sample input signals with frequencies above the converter's Nyquist frequency. The noise floor stays very low at high frequencies and SINAD becomes dominated by distortion at frequencies beyond Nyquist.

#### **Recommended Layout**

To obtain the best performance from the LTC2312-14 a printed circuit board is required. Layout for the printed circuit board (PCB) should ensure the digital and analog signal lines are separated as much as possible. In particular, care should be taken not to run any digital clocks or signals alongside analog signals or underneath the ADC. Figure 16 through Figure 20 is an example of a recommended PCB layout. A single solid ground plane is used. Bypass capacitors to the supplies are placed as close as possible to the supply pins. Low impedance common returns for these bypass capacitors are essential to the low noise operation of the ADC. The analog input traces are screened by ground. For more details and information refer to DC1563, the evaluation kit for the LTC2312-14.

#### **Bypassing Considerations**

High quality tantalum and ceramic bypass capacitors should be used at the  $V_{DD}$ , OV<sub>DD</sub> and REF pins. For optimum performance, a 2.2µF ceramic chip capacitor should be used for the  $V_{DD}$  and  $OV_{DD}$  pins. The recommended bypassing for the REF pin is also a low ESR, 2.2µF ceramic capacitor. The traces connecting the pins and the bypass capacitors must be kept as short as possible and should be made as wide as possible avoiding the use of vias.

All analog circuitry grounds should be terminated at the LTC2312-14. The ground return from the LTC2312-14 to the power supply should be low impedance for noise free operation. Digital circuitry grounds must be connected to the digital supply common.



In applications where the ADC data outputs and control signals are connected to a continuously active microprocessor bus, it is possible to get errors in the conversion results. These errors are due to feed-through from the

LTC CONFIDENTIAL-FOR CUSTOMER USE ONL  $(E5)$  VDD  $\binom{2}{5}$ VCCIO  $\binom{2}{2}$ 1.8V <u><sub>대</sub> 중</del> 전 자주</u> C<sub>23</sub> C<sub>24</sub>  $C<sub>27</sub>$ .<br>∷r∩  $C14$ J2  $\widehat{E}$  $11111$ R112<br>R112  $\overline{U}$  $\overline{u}$ <sub>12</sub>  $C28$ E<sub>1</sub>  $U14$ CTS8 SAR ADC **SPFFD HIGH**  $1505$ 이 10년<br>10년  $\overline{u}$ 4 $\overline{u}$ 있  $C4$ U11 ligwww.linear.com **ANDIERA**  $\overline{11}$  $C31 =$ D4 LOOMHZ  $\overline{113}$ N<br>P COUPLING R32<sub>m</sub> 이미요 점잡  $3.3U<sub>DD</sub>$  $C32 =$  $JPI$  $J<sub>4</sub>$ に川島  $R_{31} = \frac{1}{R_{12}}$ Ш U6 US 드C17요  $E<sub>R16</sub>$  DEMO C19C12 R9 **CIRCUIT**  $c\overline{11}$  $ATN$  JP2 1563A-US SCK CSL SDO 'n 00-4.096U  $R24 = R21$ 39 DC590 ć J5 JTAG 10 **JNFAR** 12

microprocessor to the successive approximation comparator. The problem can be eliminated by forcing the microprocessor into a "Wait" state during conversion or by using three-state buffers to isolate the ADC data bus.







**Figure 18. Layer 2 GND Plane**





**Figure 19. Layer 3 PWR Plane**



**Figure 20. Layer 4 Bottom Layer**





**Figure 21. Partial 1563 Demo Board Schematic**



### PACKAGE DESCRIPTION

**Please refer to http://www.linear.com/designtools/packaging/ for the most recent package drawings.**



**TS8 Package 8-Lead Plastic TSOT-23**

6. JEDEC PACKAGE REFERENCE IS MO-193





### REVISION HISTORY





### TYPICAL APPLICATION

**Low Jitter Clock Timing with RF Sine Generator Using Clock Squaring/Level-Shifting Circuit and Re-Timing Flip-Flop**



### RELATED PARTS

